

<b>Notice of References Cited</b>	Application/Control No. 10/054,992	Applicant(s)/Patent Under Reexamination IWAMURA ET AL.	
	Examiner Huy D Nguyen	Art Unit 2617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,760,594	07-2004	Murasawa et al.	455/512
*	B	US-6,532,227	03-2003	Leppisaari et al.	455/450
*	C	US-5,627,876	05-1997	Moon, Billy G.	455/426.1
*	D	US-5,570,411	10-1996	Sicher, Alan	455/450
*	E	US-5,740,537	04-1998	Beming et al.	455/450
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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